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## **Certified Reference Material**

## Certificate of Analysis

ISO 17034:2016

ISO/IEC 17025:2017



Product ID: MBH-AL6063-20

Product Description: Aluminum Alloy, AA6063 / A96063

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

			Cer	tified value	es listed in wt."	% with as	sociated u	ncertainties			
В	0.0011	$\pm 0.0008$	Co	0.0003	$\pm 0.0002$	Cr	0.0088	$\pm 0.0006$	Cu	0.030	± 0.001
Fe	0.156	$\pm 0.004$	Ga	0.0109	± 0.0006	Mg	0.481	± 0.008	Mn	0.023	± 0.001
Ni	0.0043	± 0.0004	Pb	0.0010	± 0.0004	Si	0.46	± 0.02	Ti	0.0107	± 0.0005
V	0.0115	+ 0 0007	Zn	0.0064	+ 0 0004	Zr	0.0011	+ 0.0002			

## Indicative Values listed in ppm

Ag	(1)	Αl	(98.8%)	As	(<10)	Be	(<1)	Bi	(<20)	Ca	(30)	Cd	(<1)
Li	(10)	Р	(<50)	Sh	(<10)	Sn	(10)	Sr	(<1)				

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N<sub>prod</sub> is the number of units produced and N<sub>min</sub> is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U<sub>hom</sub>). Uncertainty of the material is calculated by eguation 2, where H=U<sub>hom</sub>, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

1. 
$$N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$
 2.  $U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$ 

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- LGC Standards Manchester, NH
- RSML Bengaluru, India
- NSL Analytical Services Cleveland, OH
- Laboratory Testing, Inc. Hatfield, PA
- Connecticut Metallurgical, Inc. East Hartford, CT
- IMR Test Labs Lansing NY
- SGS MSi Melrose Park, IL
- Scrooby's Laboratory Service Rynfield, South Africa
- Applied Technical Services Marietta, GA
- FAG Laboratories Liverpool NY
- AnchorCert Analytical Birmingham, UK
- Luvak Inc. Boviston, MA

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

October 7, 2021



ISO 17034 Accredited: Reference Materials Producer Certificate # 2848 02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01



## The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Ag	Al	As	В	Be	Bi	Ca	Cd	Co	Cr	Cu	Fe	Ga	Li
1	0.0001	98.770	0.00003	0.0001	0.00001	0.0017	0.0003	0.00002	0.0001	0.0070	0.0258	0.1440	0.0088	0.0001
2	0.0001	98.800	0.0005	0.0002	0.0001	0.0024	0.0007	0.00003	0.0001	0.0076	0.0260	0.1450	0.0105	0.0001
3	0.0001	98.800	<0.0001	0.0008	< 0.0001	<0.0001	0.0007	0.0001	0.0002	0.0078	0.0278	0.1470	0.0105	0.0001
4	0.0003	98.810	<0.001	0.0008	<0.0001	<0.0001	0.0011	<0.0001	0.0002	0.0079	0.0280	0.1532	0.0107	0.0021
5	< 0.0005		< 0.001	0.0011	< 0.0001	<0.001	0.0019	< 0.0005	0.0005	0.0080	0.0280	0.1534	0.0109	<0.0001
6	<0.0005		<0.001	0.0022	< 0.0005	<0.001	0.0050	<0.0005	0.0005	0.0086	0.0290	0.1539	0.0109	<0.0005
7	<0.001		<0.005	0.0022	< 0.001	<0.001	0.0106	<0.001	0.0005	0.0086	0.0290	0.1550	0.0110	<0.001
8	< 0.001			<0.0001	< 0.001	< 0.002	<0.0005	< 0.001	<0.0005	0.0088	0.0292	0.1560	0.0110	
9				<0.001				<0.001	<0.0005	0.0090	0.0300	0.1562	0.0112	
10									<0.001	0.0090	0.0300	0.1570	0.0115	
11									<0.001	0.0092	0.0304	0.1570	0.0125	
12									<0.001	0.0096	0.0310	0.1600		
13										0.0100	0.0322	0.1617		
14										0.0100	0.0329	0.1655		
15										0.0110	0.0336	0.1680		
16											0.0340			
17														
18														
19														
20														
21														
Mean	0.0001	98.795	0.0003	0.0011	0.00003	0.0021	0.0029	0.0001	0.0003	0.0088	0.0298	0.1555	0.0109	0.0006
STDV	0.0001	0.0174	0.0003	0.0009	0.00003	0.0005	0.0037	0.00004	0.0002	0.0011	0.0025	0.0068	0.0009	0.0010
Certified	(0.0001)	(98.8)	(<0.001)	0.0011	(<0.0001)	(<0.002)	(0.003)	(<0.0001)	0.0003	0.0088	0.030	0.156	0.0109	(0.001)
U <sub>CRM</sub>				0.0008				,	0.0002	0.0006	0.001	0.004	0.0006	
Methods	O,IM,I	0,1	O,IM,I	O,IM,I	O,IM,I	O,IM,I	O,IM,I	O,IM,I	O,I,IM	O,I,IM,X	O,I,IM,X	O,I,IM,X	O,IM,I,X	O,IM,I

	Mg	Mn	Ni	Р	Pb	Sb	Si	Sn	Sr	Ti	٧	Zn	Zr	
1	0.4550	0.0195	0.0030	0.0015	0.0003	0.0010	0.3900	0.0002	0.0001	0.0097	0.0093	0.0050	0.0006	
2	0.4570	0.0200	0.0036	0.0025	0.0005	<0.0005	0.4132	0.0007	0.0001	0.0100	0.0102	0.0055	0.0007	
3	0.4680	0.0210	0.0037	0.0092	0.0009	<0.001	0.4370	0.0008	0.0002	0.0100	0.0106	0.0059	0.0010	
4	0.4747	0.0213	0.0040	<0.0001	0.0010		0.4520	0.0010	<0.0001	0.0104	0.0107	0.0060	0.0010	
5	0.4770	0.0219	0.0040	<0.002	0.0011		0.4620	0.0010	<0.0001	0.0104	0.0110	0.0060	0.0010	
6	0.4780	0.0226	0.0042	<0.002	0.0014		0.4624	0.0012	< 0.0005	0.0106	0.0110	0.0060	0.0013	
7	0.4780	0.0229	0.0043	<0.005	0.0015		0.4670	0.0013	< 0.0005	0.0106	0.0110	0.0061	0.0014	
8	0.4819	0.0230	0.0044		0.0017		0.4700	0.0020	<0.001	0.0108	0.0111	0.0062	0.0014	
9	0.4850	0.0231	0.0044		<0.005		0.4740	0.0023	<0.001	0.0110	0.0112	0.0064	0.0014	
10	0.4850	0.0237	0.0045		<0.005		0.4830	0.0037	<0.01	0.0110	0.0119	0.0065	<0.001	
11	0.4850	0.0240	0.0045				0.4950	<0.0005		0.0111	0.0119	0.0067	<0.002	
12	0.4860	0.0244	0.0050				0.5179	<0.001		0.0113	0.0120	0.0070		
13	0.4962	0.0245	0.0050					<0.001		0.0115	0.0131	0.0073		
14	0.5000	0.0248	0.0050					<0.005		0.0119	0.0131	0.0074		
15	0.5068										0.0140	0.0074		
16														
17														
18														
19														
20														
21														
Mean	0.4809	0.0226	0.0043	0.0044	0.0010	0.0010	0.4603	0.0014	0.0001	0.0107	0.0115	0.0064	0.0011	
STDV	0.0142	0.0017	0.0006	0.0042	0.0005		0.0346	0.0010	0.0001	0.0006	0.0012	0.0007	0.0003	
Certified	0.481	0.023	0.0043	(<0.005)	0.0010	(<0.001)	0.46	(0.001)	(<0.0001)	0.0107	0.0115	0.0064	0.0011	
UCRM	0.008	0.001	0.0004		0.0004		0.02			0.0005	0.0007	0.0004	0.0002	
Methods	O,I,IM,X	O,I,IM,X	O,IM,I,X	O,IM,I	O,IM,I	O,IM	O,I,IM	O,I,IM,X	O,IM,I	O,I,IM,X	O,I,IM,X	O,I,IM,X	O,IM,I	

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

